Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/790,804	TAKAMURA	
Examiner	Art Unit	
A. Sefer	2826	

SEARCHED					
Class	Subclass	Date	Examiner		
257	290-293	1/21/2005	A.S.		
1	461-463	1	V		

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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	DATE	EXMR
BRS	2/20/2005	A.S.